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VTS 2012
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Organizers: M. NICOLAIDIS - TIMA, Y. Zorian - Synopsys

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Organizers & Speakers: A. BOSIO, L. DILILLO - LIRMM
Authors: A. BOSIO, L. DILILLO, P. GIRARD, S. PRAVOSSOUDOVITCH, A. VIRAZEL – LIRMM

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Organizer: C. THIBEAULT - Ecole de technologie superieure
Panelists:

- H. MANHAEVE - Q-Qtar
- A. SINGH - Auburn U.
- C. THIBEAULT - ETS